



ALPHA & OMEGA
SEMICONDUCTOR

AON7403

30V P-Channel MOSFET

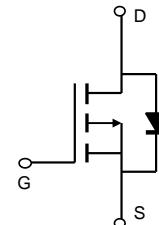
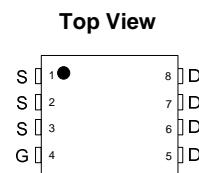
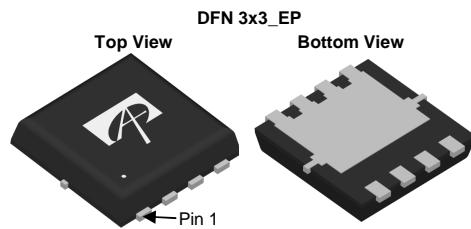
General Description

The AON7403 uses advanced trench technology to provide excellent $R_{DS(ON)}$, and ultra-low low gate charge with a 25V gate rating. This device is suitable for use as a load switch or in PWM applications.

Product Summary

V_{DS}	-30V
I_D (at $V_{GS}=-10V$)	-29A
$R_{DS(ON)}$ (at $V_{GS}=-10V$)	< 18mΩ
$R_{DS(ON)}$ (at $V_{GS}=-5V$)	< 36mΩ

100% UIS Tested



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 25	V
Continuous Drain Current $T_C=25^\circ\text{C}$	I_D	-29	A
		-18	
Pulsed Drain Current ^C	I_{DM}	-80	
Continuous Drain Current $T_A=25^\circ\text{C}$	I_{DSM}	-11	A
		-8.5	
Avalanche Current ^C	I_{AR}	24	A
Repetitive avalanche energy $L=0.1\text{mH}$ ^C	E_{AR}	29	mJ
Power Dissipation ^B	P_D	25	W
		10	
Power Dissipation ^A	P_{DSM}	3.1	W
		2	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	30	40	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		60	75	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	4.2	5	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 25\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.7	-2.2	-3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-80			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-8\text{A}$ $T_J=125^\circ\text{C}$		14 20	18 25	$\text{m}\Omega$
		$V_{GS}=-5\text{V}, I_D=-5\text{A}$		26	36	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-8\text{A}$		20		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-22	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		1130	1400	pF
C_{oss}	Output Capacitance			240		pF
C_{rss}	Reverse Transfer Capacitance			155		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		5.8	8	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-8\text{A}$		18	24	nC
Q_{gs}	Gate Source Charge			5.5		nC
Q_{gd}	Gate Drain Charge			3.3		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=1.8\Omega, R_{\text{GEN}}=3\Omega$		8.7		ns
t_r	Turn-On Rise Time			8.5		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			18		ns
t_f	Turn-Off Fall Time			7		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-8\text{A}, dI/dt=500\text{A}/\mu\text{s}$		12	16	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-8\text{A}, dI/dt=500\text{A}/\mu\text{s}$		26		nC

A. The value of R_{qJA} is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, in a still air environment with $TA = 25^\circ\text{C}$. The Power dissipation PDSM is based on $R_{qJA} t \leq 10\text{s}$ value and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 150°C may be used if the PCB allows it.

B. The power dissipation PD is based on $T_J(\text{MAX})=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_J(\text{MAX})=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $TJ = 25^\circ\text{C}$.

D. The R_{qJA} is the sum of the thermal impedance from junction to case R_{qJC} and case to ambient.

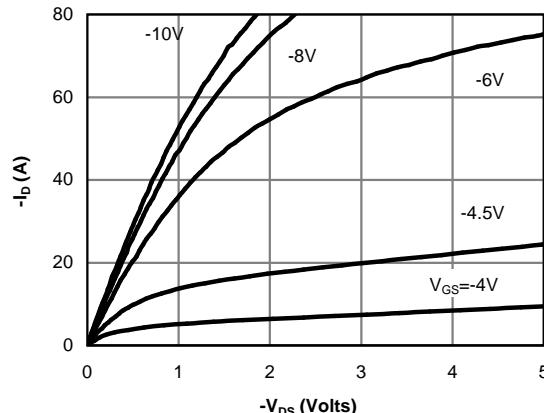
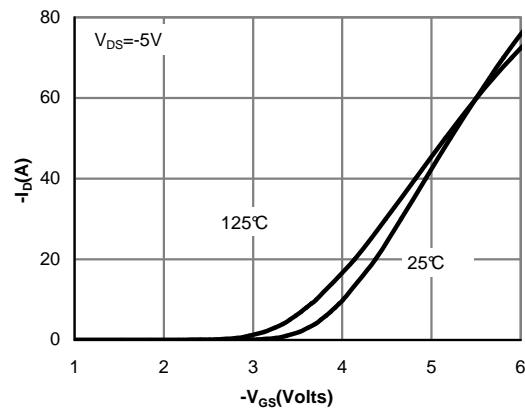
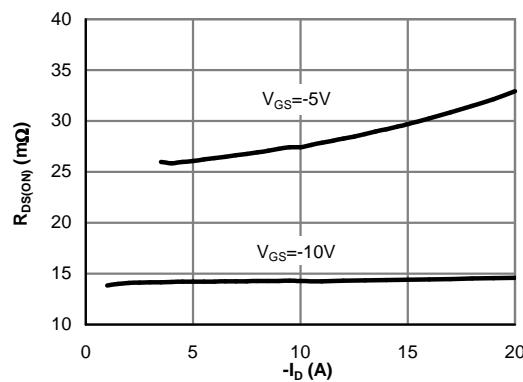
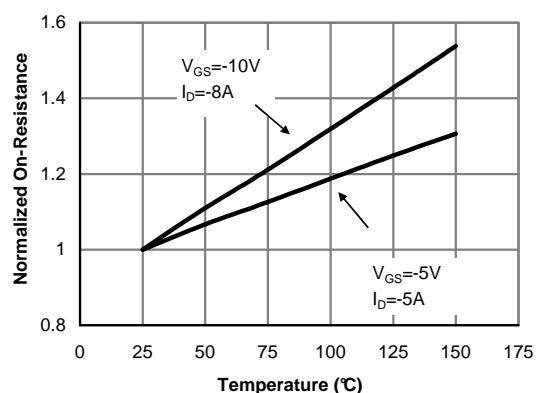
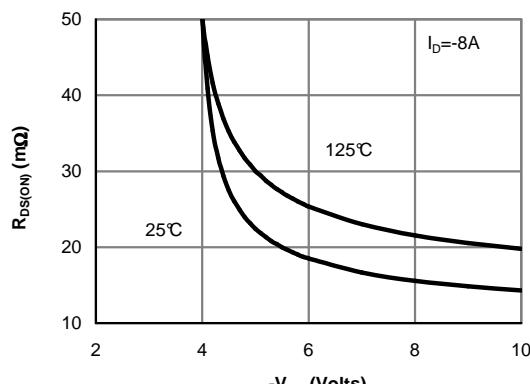
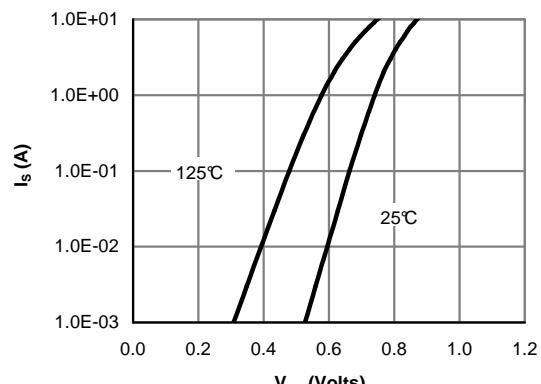
E. The static characteristics in Figures 1 to 6 are obtained using $<300\text{ms}$ pulses, duty cycle 0.5% max.

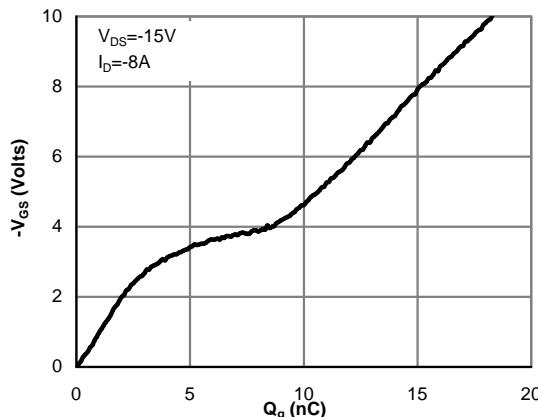
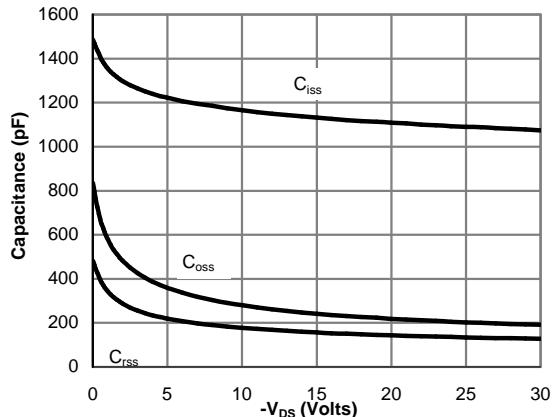
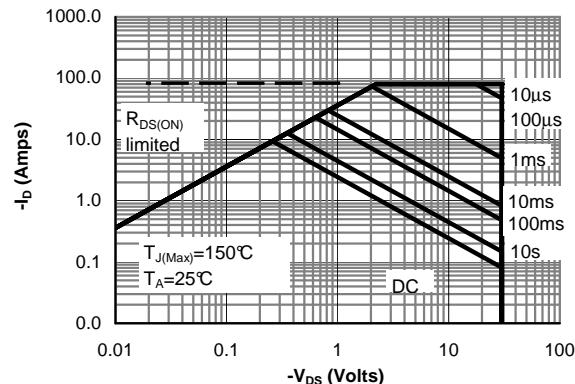
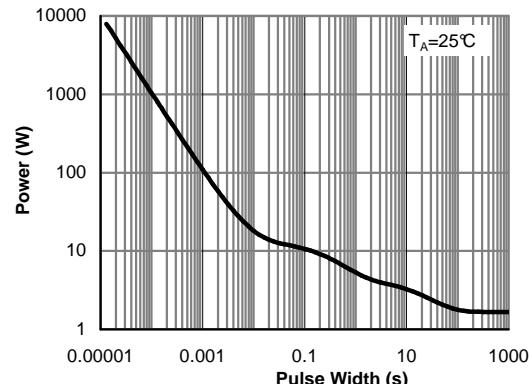
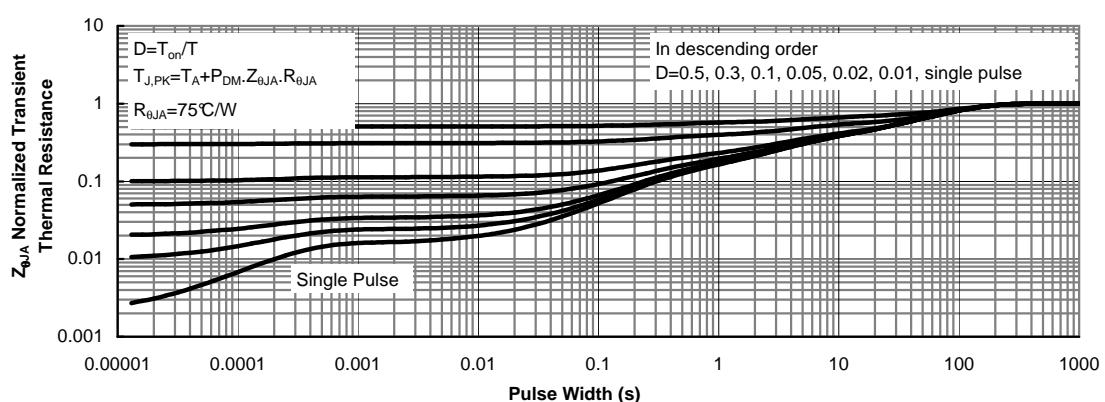
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_J(\text{MAX})=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

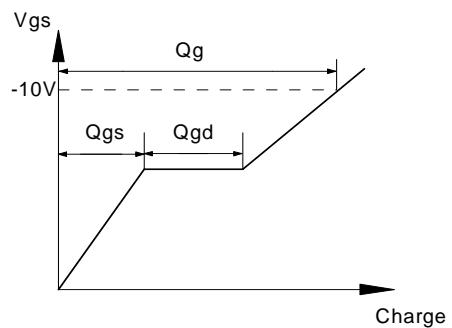
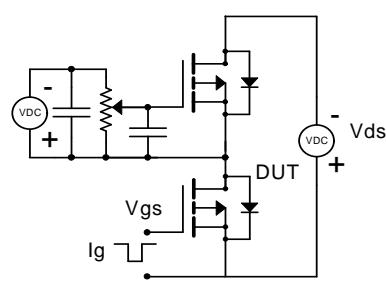
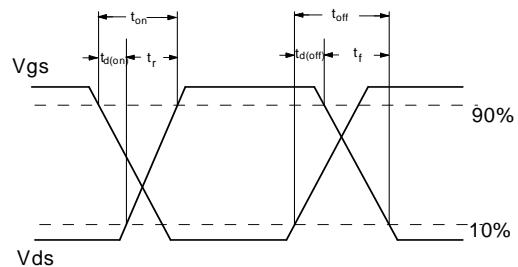
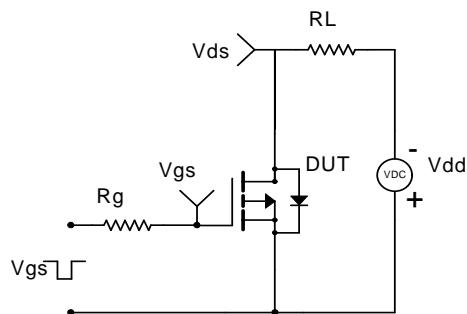
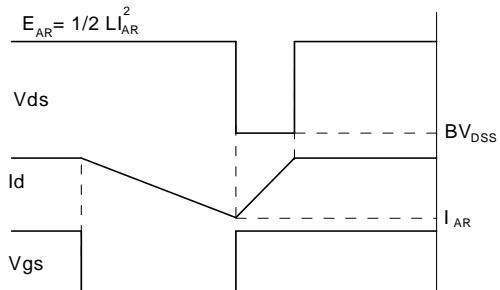
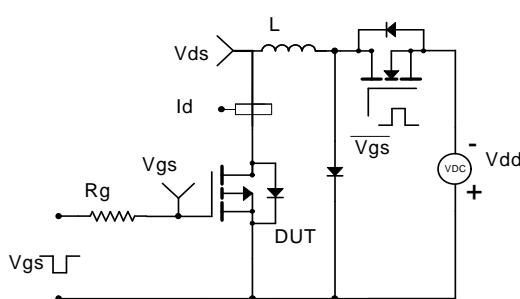
G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with $TA=25^\circ\text{C}$.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
